FORM,PTO-1449	SERIAL NO. 10/532894	CASE NO.
./	- Not yet assigned	10808/235
LIST OF PATENTS AND PUBLICATIONS FOR	FILING DATE	GROUP ART UNIT
APPLICANT'S INFORMATION DISCLOSURE	Herewith	2823 NA
STATEMENT		0105
(use several sheets if necessary)	APPLICANT(S): Josef Böck et a	1.

EXAMINER INITIAL		DOCUMENT NUMBER Number-Kind Code (if known)	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
HAO	A1	US 2002/0079554 A1	June 27, 2002	Okawa et al.		
7	A2	US 2001/0045619 A1	November 29, 2001	Dekker et al.		
80	A3	4,882,294	November 21, 1999	Christenson		
SURC	A4	4,379,726	April 12, 1983	Kamamaru et al.		
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FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER Number-Kind Code (if known)	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES OR NO
1100	A5	DE 100 44 838 A1	September 11, 2000	Germany		
	A6	WO 97/17726	May 15, 1997	WO		
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ANG.	A12	Bipolar Transistor with Pedestal Subcollector Regions Self-Aligned Underneath Field Oxide Regions, pgs. 252-253, 700 IBM Technical Disclosure Bulletin, Vol. 31, No. 3, August 1988.
J	A13	M. Racanelli, K. Schuegraf, A. Kalburge, A. Kar-Ray, B. Shen, C. Hu, D. Chapek, D. Howard, D. Quon, F. Wang, G. U'ren, L. Lao, J. Zheng, J. Zhang, K. Bell, K. Yin, P. Joshi, S. Akhtar, S. Vo, T. Lee, W. Shi and P. Kempf, <i>Ultra High Speed SiGe NPN for Advanced BiCMOS Technology</i> , Silicon RF Platform Technologies, Conexant Systems, Inc.
\bigvee	A14	Copy of International Search Report from corresponding PCT patent application number PCT/DE03/03552.
AR	A15	Copy of Examination Report from corresponding PCT patent application number PCT/DE03/03552.

EXAMPRICE LEGIT	padh DATE CONSIDERED 9/29/07

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.